

Date Created : 2007/11/12
Date Issued On : 2007/11/29
PCN# : Q3073508-A

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Implementation of change:
Expected 1st Device Shipment Date: 2007/12/26

Earliest Year/Work Week of Changed Product: 52-2007

Change Type Description: Alternate Assembly/Test Location/Qualification

Description of Change (From): FAN5xxxUC WL-CSP products are assembled and tested at the AMKOR facility (A5) in North Carolina, USA

Description of Change (To): FAN5xxxUC WL-CSP products will be assembled at the AMKOR facility (K4) in Korea and tested at the AMKOR facility (T3) in Taiwan.

Reason for Change : Manufacturing activities at the AMKOR facility (A5) in North Carolina will be phased out as this facility will focus on process development.

Qual/REL Plan Numbers : Q20070202

Qualification :

F20070202

Results/Discussion

Test: (Autoclave)					
Lot	Device	96-HOURS	Failure Code		
Q20070202AAACLVF	FAN5309UCX	0/77			
Q20070202ABACLVF	FAN5309UCX	0/77			
Q20070202ACACLVF	FAN5309UCX	0/77			
Q20070202ADACLVF	FAN5309UCX	0/77			
Test: (Board Level Temperature Cycle)					
Lot	Device	500-HOURS	1000-HOURS	1500	Failure Code

Q20070202BABTMCLF	TEST	0/77			
			0/77		
				0/77	

Test: (Dynamic Op Life)

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070202AADOPLF	FAN5309UCX	0/77			
			0/77		
				0/77	
Q20070202ABDOPLF		0/77			
			0/77		
				0/77	
Q20070202ACDOPLF		0/77			
			0/77		
				0/77	
Q20070202ADDOPLF		0/77			
			0/77		
				0/77	

Test: (High Temperature Storage Life)

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070202AAHTSLF		0/77			
			0/77		
				0/77	
Q20070202ABHTSLF		0/77			
			0/77		
				0/77	
Q20070202ACHTSLF		0/77			
			0/77		
				0/77	
Q20070202ADHTSLF		0/77			
			0/77		
				0/77	

Test: (MOIS)

Lot	Device	24-HOURS	Failure Code
Q20070202AAMOISF	FAN5309UCX	0/100	
Q20070202ABMOISF	FAN5309UCX	0/100	
Q20070202ACMOISF	FAN5309UCX	0/100	
Q20070202ADMOISF	FAN5309UCX	0/100	

Test: -40C, 125C (Temperature Cycle)

Lot	Device	500-CYCLES	1000-CYCLES	Failure Code
Q20070202AATMCL2F	FAN5309UCX	0/77		
Q20070202AATMCL2F	FAN5309UCX		0/77	
Q20070202ABTMCL2F	FAN5309UCX	0/77		
Q20070202ABTMCL2F	FAN5309UCX		0/77	
Q20070202ACTMCL2F	FAN5309UCX	0/77		
Q20070202ACTMCL2F	FAN5309UCX		0/77	
Q20070202ADTMCL2F	FAN5309UCX	0/77		
Q20070202ADTMCL2F	FAN5309UCX		0/77	

Test: 130C (Highly Accelerated Stress Test)

Lot	Device	96-HOURS	Failure Code
Q20070202AAHAST1F	FAN5309UCX	0/45	
Q20070202ABHAST1F	FAN5309UCX	0/45	
Q20070202ACHAST1F	FAN5309UCX	0/45	
Q20070202ADHAST1F	FAN5309UCX	0/45	

Test: Reflow (260C high Temp) (Reflow)

Lot	Device	Results	Failure Code
Q20070202AAREFL2F	FAN5309UCX	0/100	
Q20070202ABREFL2F	FAN5309UCX	0/100	
Q20070202ACREFL2F	FAN5309UCX	0/100	
Q20070202ADREFL2F	FAN5309UCX	0/100	

Product Id Description :

Affected FSIDs :

FAN5350UCX		
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